

**Notice of References Cited**

Application/Control No.

09/739,082

Applicant(s)/Patent Under  
Reexamination  
GUNN ET AL.

Examiner

Van Kim T. Nguyen

Art Unit

2661

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,304,566	10-2001	Schessel, Larry E.	370/354
	B	US-6,661,785	12-2003	Zhang et al.	370/352
	C	US-6,515,996	02-2003	Tonnby et al.	370/352
	D	US-6,411,704	06-2002	Pelletier et al.	379/230
	E	US-6,377,668	04-2002	Smock et al.	379/142.08
	F	US-6,381,320	04-2002	Creamer et al.	379/201.01
	G	US-6,337,850	01-2002	Nakano et al.	370/230
	H	US-6,333,931	12-2001	LaPier et al.	370/385
	I	US-6,317,488	11-2001	DePond et al.	379/93.35
	J	US-6,253,249	06-2001	Belzile, Pierre	709/249
	K	US-6,212,261	04-2001	Meubus et al.	379/88.12
	L	US-5,917,817	06-1999	Dunn et al.	370/352
	M	US-5,805,587	09-1998	Norris et al.	370/352

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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